

SLOVENSKI STANDARD SIST EN IEC 60384-22:2024

01-september-2024

Fiksni kondenzatorji za uporabo v elektronski opremi - 22. del: Področna specifikacija - Fiksni večplastni kondenzatorji za površinsko namestitev s keramičnim dielektrikom, razred 2 (IEC 60384-22:2024)

Fixed capacitors for use in electronic equipment - Part 22: Sectional specification - Fixed surface mount multilayer capacitors of ceramic dielectric, class 2 (IEC 60384-22:2024)

Festkondensatoren zur Verwendung in Geräten der Elektronik - Teil 22: Rahmenspezifikation - Oberflächenmontierbare Vielschichtkeramik-Festkondensatoren, Klasse 2 (IEC 60384-22:2024)

Condensateurs fixes utilisés dans les équipements électroniques - Partie 22: Spécification intermédiaire - Condensateurs multicouches fixes à diélectriques en céramique pour montage en surface, de classe 2 (IEC 60384-22:2024)

standards.1ten.ai/cata10g/standards/sist/cc1414aU-4c14-4c9Z-89e1-Z6/353Z4Zbc5/sist-en-1ec-6U384-ZZ-ZU

Ta slovenski standard je istoveten z: EN IEC 60384-22:2024

ICS:

31.060.10 Fiksni kondenzatorji Fixed capacitors

SIST EN IEC 60384-22:2024 en

iTeh Standards (https://standards.iteh.ai) Document Preview

SIST EN IEC 60384-22:2024

https://standards.iteh.ai/catalog/standards/sist/ccf414a0-4c14-4c92-89e1-267353242bc5/sist-en-iec-60384-22-2024

EUROPEAN STANDARD NORME EUROPÉENNE FUROPÄISCHE NORM

EN IEC 60384-22

August 2024

ICS 31.060.10

Supersedes EN IEC 60384-22:2019

English Version

Fixed capacitors for use in electronic equipment - Part 22: Sectional specification - Fixed surface mount multilayer capacitors of ceramic dielectric, Class 2 (IEC 60384-22:2024)

Condensateurs fixes utilisés dans les équipements électroniques - Partie 22: Spécification intermédiaire -Condensateurs multicouches fixes à diélectriques en céramique pour montage en surface, de Classe 2 (IEC 60384-22:2024)

Festkondensatoren zur Verwendung in Geräten der Elektronik - Teil 22: Rahmenspezifikation -Oberflächenmontierbare Vielschichtkeramik-Festkondensatoren, Klasse 2 (IEC 60384-22:2024)

This European Standard was approved by CENELEC on 2024-07-26. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the CEN-CENELEC Management Centre or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the CEN-CENELEC Management Centre has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Bulgaria, Croatia, Cyprus, the Czech Republic, Denmark, Estonia, Finland, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, the Netherlands, Norway, Poland, Portugal, Republic of North Macedonia, Romania, Serbia, Slovakia, Slovenia, Spain, Sweden, Switzerland, Türkiye and the United Kingdom.



European Committee for Electrotechnical Standardization Comité Européen de Normalisation Electrotechnique Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

EN IEC 60384-22:2024 (E)

European foreword

The text of document 40/3120/FDIS, future edition 4 of IEC 60384-22, prepared by IEC/TC 40 "Capacitors and resistors for electronic equipment" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 60384-22:2024.

The following dates are fixed:

- latest date by which the document has to be implemented at national (dop) 2025-04-26 level by publication of an identical national standard or by endorsement
- latest date by which the national standards conflicting with the (dow) 2027-07-26 document have to be withdrawn

This document supersedes EN IEC 60384-22:2019 and all of its amendments and corrigenda (if any).

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CENELEC shall not be held responsible for identifying any or all such patent rights.

Any feedback and questions on this document should be directed to the users' national committee. A complete listing of these bodies can be found on the CENELEC website.

Endorsement notice

The text of the International Standard IEC 60384-22:2024 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standard indicated:

IEC 60063 NOTE Approved as EN 60063

IEC 60068-1:2013 NOTE Approved as EN 60068-1:2014 (not modified)

IEC 60384-14 NOTE Approved as EN IEC 60384-14

IEC 60384-22-1:2004 NOTE Approved as EN 60384-22-1:2004 (not modified)

EN IEC 60384-22:2024 (E)

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cencenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	EN/HD	<u>Year</u>
IEC 60068-2-58	-	Environmental testing - Part 2-58: Tests - Test Td: Test methods for solderability, resistance to dissolution of metallization and to soldering heat of surface mounting devices (SMD)	EN 60068-2-58	-
IEC 60384-1	2021	Fixed capacitors for use in electronic equipment - Part 1: Generic specification	EN IEC 60384-1	2021
IEC 61193-2	2007	Quality assessment systems - Part 2: Selection and use of sampling plans for inspection of electronic components and packages	EN 61193-2	2007

https://standards.iteh.aj/catalog/standards/sist/ccf414a0-4c14-4c92-89e1-267353242bc5/sist-en-iec-60384-22-202

iTeh Standards (https://standards.iteh.ai) Document Preview

SIST EN IEC 60384-22:2024

https://standards.iteh.ai/catalog/standards/sist/ccf414a0-4c14-4c92-89e1-267353242bc5/sist-en-iec-60384-22-2024



IEC 60384-22

Edition 4.0 2024-06

INTERNATIONAL STANDARD

NORME INTERNATIONALE

Fixed capacitors for use in electronic equipment – S

Part 22: Sectional specification – Fixed surface mount multilayer capacitors of ceramic dielectric, Class 2

Condensateurs fixes utilisés dans les équipements électroniques – Partie 22: Spécification intermédiaire – Condensateurs multicouches fixes à diélectriques en céramique pour montage en surface, de Classe 2

...,

INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

COMMISSION ELECTROTECHNIQUE INTERNATIONALE

ICS 31.060.10 ISBN 978-2-8322-8919-8

Warning! Make sure that you obtained this publication from an authorized distributor.

Attention! Veuillez vous assurer que vous avez obtenu cette publication via un distributeur agréé.

CONTENTS

-2-

FC	DREWO	RD	6
1	Scop	e	8
2	Norm	ative references	8
3	Term	s and definitions	8
4		erred ratings and characteristics	
•	4.1	Preferred characteristics	
	4.1	Preferred values of ratings	
	4.2.1	Rated temperature (T_{R})	
		· · · · · · · · · · · · · · · · · · ·	
	4.2.2		
	4.2.3		10
	4.2.4	Preferred values of nominal capacitance and associated tolerance values	10
	4.2.5	Temperature characteristic of capacitance	11
	4.2.6	Dimensions	11
5	Test	and measurement procedures	12
	5.1	General	12
	5.2	Special preconditioning	12
	5.3	Measuring conditions	12
	5.4	Mounting	12
	5.5	Visual examination and check of dimensions	12
	5.5.1	General	
	5.5.2	Visual examination	12
	5.5.3	Requirements	12
	5.6	Electrical tests	14
	5.6.1	Capacitance	60
	5.6.2	5	
	5.6.3	Insulation resistance	15
	5.6.4	Voltage proof	
	5.6.5		17
	5.6.6	Equivalent series resistance [ESR] (if required by the detail specification)	17
	5.7	Temperature characteristic of capacitance (reference temperature 20 °C)	17
	5.7.1	Special preconditioning	17
	5.7.2	Measuring conditions	17
	5.7.3	Requirements	18
	5.8	Shear test	18
	5.9	Substrate bending test	18
	5.9.1	General	
	5.9.2	Initial measurement	19
	5.9.3	Final inspection	
	5.10	Resistance to soldering heat	
	5.10.		
	5.10.		
	5.10.		
	5.10.		
	5.10.	5 Recovery	20

= 40.0			
5.10.6	Final inspection, measurements and requirements		
	lderability		
5.11.1	General		
5.11.2	Test conditions		
5.11.3	Recovery	22	
5.11.4	Final inspection, measurements and requirements	22	
5.12 Ra	pid change of temperature	22	
5.12.1	General	22	
5.12.2	Special preconditioning	22	
5.12.3	Initial measurement	22	
5.12.4	Number of cycles	22	
5.12.5	Recovery	22	
5.12.6	Final inspection, measurements and requirements	23	
5.13 Cli	matic sequence	23	
5.13.1	General	23	
5.13.2	Special preconditioning	23	
5.13.3	Initial measurement	23	
5.13.4	Dry heat	23	
5.13.5	Damp heat, cyclic, Test Db, first cycle		
5.13.6	Cold		
5.13.7	Damp heat, cyclic, Test Db, remaining cycles		
5.13.8	Final inspection, measurements and requirements		
	mp heat, steady state		
5.14.1	General		
5.14.2	Special preconditioning		
5.14.3	Initial measurement		
5.14.4	Test conditions		
s://standarc5.14.5ai	/_Recovery		
5.14.6	Final inspection, measurements and requirements		
	durance		
5.15.1	General		
5.15.2	Special preconditioning		
5.15.3	Initial measurement		
5.15.4	Test conditions		
5.15.5			
	Recovery		
5.15.6	Final inspection, measurements and requirements		
	bustness of terminations (only for capacitors with strip termination)		
5.16.1	General		
5.16.2	Test conditions		
5.16.3	Final inspection and requirements		
	mponent solvent resistance (if required)		
	lvent resistance of the marking (if required)		
	celerated damp heat, steady state (if required)		
5.19.1	General		
5.19.2	Initial measurement		
5.19.3	Conditioning		
5.19.4	Recovery		
5.19.5	Final measurements		
6 Marking		30	

6.2	1 General	
0.2	2 Information for marking	30
6.3	3 Marking on the body	30
6.4	4 Requirements for marking	30
6.5	5 Marking of the packaging	30
6.6	6 Additional marking	30
7 Ir	Information to be given in a detail specification	31
7.1	1 General	31
7.2	2 Outline drawing and dimensions	31
7.3	3 Mounting	31
7.4	4 Rating and characteristics	31
7	7.4.1 General	31
7	7.4.2 Nominal capacitance range	31
7	7.4.3 Particular characteristics	32
7	7.4.4 Soldering	32
7.5	5 Marking	32
8 C	Quality assessment procedures	32
8.1	1 Primary stage of manufacture	32
8.2	, ,	
	·	
8.3		
8.3 8.4	4 Qualification approval	32
8.4	•	
8.4 8	8.4.1 General	32
8.4 8 8 8 Annex	8.4.1 General	32 dures32 33 fixed
8.4 8 8 8 Annex surfac	8.4.1 General	32 dures 32 33 fixed 38 c,
8.4 8 8 8 Annex surfac Annex	8.4.1 General	32 dures 32 33 fixed 38 5, 394
8.4 8 8 Annex surfac Annex Class B.1	8.4.1 General	32 dures 32 33 fixed 38 5, 39 39
8.4 8 8 Annex surfact Annex Class B.1 B.2	8.4.1 General	
8.4 8 8 Annex surfact Annex Class B.1 B.2	8.4.1 General 8.4.2 Qualification approval on the basis of the fixed sample size proces 8.4.3 Tests x A (normative) Guidance for the specification and coding of dimensions of ce mount multilayer capacitors of ceramic dielectric, Class 2 x B (normative) Capacitance ageing of fixed capacitors of ceramic dielectrics 2 1 General 2 Law of capacitance ageing 3 Capacitance measurements and capacitance tolerance	32 dures 32 33 fixed 38 5, 39 39 40
8.4 8 8 Annex surfac Annex Class B.1 B.2 B.3	8.4.1 General 8.4.2 Qualification approval on the basis of the fixed sample size proced 8.4.3 Tests x A (normative) Guidance for the specification and coding of dimensions of ce mount multilayer capacitors of ceramic dielectric, Class 2 x B (normative) Capacitance ageing of fixed capacitors of ceramic dielectrics 2 General Law of capacitance ageing Capacitance measurements and capacitance tolerance Special preconditioning (see 5.2)	32 dures
8.4 8 8 Annex surfact Annex Class B.1 B.2 B.3 B.4 Annex	8.4.1 General 8.4.2 Qualification approval on the basis of the fixed sample size proces 8.4.3 Tests x A (normative) Guidance for the specification and coding of dimensions of ce mount multilayer capacitors of ceramic dielectric, Class 2 x B (normative) Capacitance ageing of fixed capacitors of ceramic dielectrics 2 General Law of capacitance ageing Capacitance measurements and capacitance tolerance Special preconditioning (see 5.2) x C (normative) Temperature characteristics of capacitance of 25 °C	32 dures 32 33 fixed 38 39 39 40 40 42
8.4 8 8 Annex surfact Annex B.1 B.2 B.3 B.4 Annex	8.4.1 General 8.4.2 Qualification approval on the basis of the fixed sample size proces 8.4.3 Tests x A (normative) Guidance for the specification and coding of dimensions of ce mount multilayer capacitors of ceramic dielectric, Class 2 x B (normative) Capacitance ageing of fixed capacitors of ceramic dielectrics 2 1 General 2 Law of capacitance ageing 3 Capacitance measurements and capacitance tolerance 4 Special preconditioning (see 5.2) x C (normative) Temperature characteristics of capacitance of 25 °C	32 dures
8.4 8 8 Annex surface Annex Class B.1 B.2 B.3 B.4 Annex Annex D.1	8.4.1 General 8.4.2 Qualification approval on the basis of the fixed sample size proces 8.4.3 Tests x A (normative) Guidance for the specification and coding of dimensions of ce mount multilayer capacitors of ceramic dielectric, Class 2 x B (normative) Capacitance ageing of fixed capacitors of ceramic dielectrics 2 1 General 2 Law of capacitance ageing 3 Capacitance measurements and capacitance tolerance 4 Special preconditioning (see 5.2) x C (normative) Temperature characteristics of capacitance of 25 °C x D (normative) Quality conformance inspection 1 Formation of inspection lots	32 dures 32 33 fixed 38 5, 39 39 40 40 40 42 44
8.4 8 8 Annex surfac Annex B.1 B.2 B.3 B.4 Annex Annex D.1	8.4.1 General 8.4.2 Qualification approval on the basis of the fixed sample size proces 8.4.3 Tests x A (normative) Guidance for the specification and coding of dimensions of ce mount multilayer capacitors of ceramic dielectric, Class 2 x B (normative) Capacitance ageing of fixed capacitors of ceramic dielectrics 2 1 General 2 Law of capacitance ageing 3 Capacitance measurements and capacitance tolerance 4 Special preconditioning (see 5.2) x C (normative) Temperature characteristics of capacitance of 25 °C x D (normative) Quality conformance inspection 1 Formation of inspection lots D.1.1 Groups A and B inspection	32 dures
8.4 8 8 Annex surface Annex Class B.1 B.2 B.3 B.4 Annex Annex	8.4.1 General 8.4.2 Qualification approval on the basis of the fixed sample size proced 8.4.3 Tests x A (normative) Guidance for the specification and coding of dimensions of ce mount multilayer capacitors of ceramic dielectric, Class 2 x B (normative) Capacitance ageing of fixed capacitors of ceramic dielectric capacitors of ceramic dielectric capacitance ageing capacitance ageing capacitance ageing capacitance tolerance capacitance capacitance measurements and capacitance tolerance capacitance capacitance capacitance capacitance capacitance of 25 °C capacitance control capacitance of 25 °C capacitance control capacitance capacitance control capacitance control capacitance control capacitance capacitance control capacitance control capacitance capac	32 dures 32 33 fixed 38 5, 39 39 40 40 40 42 44 44 44
8.4 8 8 Annex surface Annex B.1 B.2 B.3 B.4 Annex Annex D.1	8.4.1 General	32 dures
8.4 8 8 Annex surface Annex Class B.1 B.2 B.3 Annex Annex D.1 D.2	8.4.1 General 8.4.2 Qualification approval on the basis of the fixed sample size proced 8.4.3 Tests x A (normative) Guidance for the specification and coding of dimensions of ce mount multilayer capacitors of ceramic dielectric, Class 2 x B (normative) Capacitance ageing of fixed capacitors of ceramic dielectric capacitance ageing of fixed capacitors of ceramic dielectric capacitance ageing 1 General 2 Law of capacitance ageing 3 Capacitance measurements and capacitance tolerance 4 Special preconditioning (see 5.2) x C (normative) Temperature characteristics of capacitance of 25 °C	32 dures
8.4 8 8 Annex surface Annex Class B.1 B.2 B.3 B.4 Annex Annex D.1 D.2 D.3 D.4	8.4.1 General 8.4.2 Qualification approval on the basis of the fixed sample size proces 8.4.3 Tests x A (normative) Guidance for the specification and coding of dimensions of ce mount multilayer capacitors of ceramic dielectric, Class 2 x B (normative) Capacitance ageing of fixed capacitors of ceramic dielectric capacitors of ceramic dielectric capacitance ageing of fixed capacitance of ceramic dielectric capacitance ageing of capacitance tolerance capacitance capacitance measurements and capacitance tolerance capacitance control capacitance of 25 °C control capacitance of 25 °C control capacitance of 25 °C control capacitance of capacitance of 25 °C control capacitance of capacitance	32 dures 32 33 fixed 38 5, 39 40 40 40 42 44 44 44 44 44 44
8.4 8 8 Annex surface Annex Class B.1 B.2 B.3 B.4 Annex D.1 D.2 D.2 D.3	8.4.1 General 8.4.2 Qualification approval on the basis of the fixed sample size proces 8.4.3 Tests x A (normative) Guidance for the specification and coding of dimensions of ce mount multilayer capacitors of ceramic dielectric, Class 2 x B (normative) Capacitance ageing of fixed capacitors of ceramic dielectrics 2 1 General 2 Law of capacitance ageing 3 Capacitance measurements and capacitance tolerance 4 Special preconditioning (see 5.2) x C (normative) Temperature characteristics of capacitance of 25 °C x D (normative) Quality conformance inspection 1 Formation of inspection lots D.1.1 Groups A and B inspection D.1.2 Group C inspection 2 Test schedule 3 Delayed delivery 4 Assessment levels 5 test schedule for quality conformance inspection	32 dures
8.4 8 8 Annex surface Annex Class B.1 B.2 B.3 B.4 Annex D.1 D.2 D.3 D.4 D.5 Annex	8.4.1 General 8.4.2 Qualification approval on the basis of the fixed sample size proces 8.4.3 Tests x A (normative) Guidance for the specification and coding of dimensions of ce mount multilayer capacitors of ceramic dielectric, Class 2 x B (normative) Capacitance ageing of fixed capacitors of ceramic dielectric capacitors of ceramic dielectric capacitance ageing of fixed capacitance of ceramic dielectric capacitance ageing of capacitance tolerance capacitance capacitance measurements and capacitance tolerance capacitance control capacitance of 25 °C control capacitance of 25 °C control capacitance of 25 °C control capacitance of capacitance of 25 °C control capacitance of capacitance	32 dures 32 33 fixed 38 5, 39 39 40 40 42 44 44 44 44 44 44 44 45 51

Figure 4 – Exposed electrodes	. 13
Figure 5 – Principal faces	.14
Figure 6 – Reflow temperature profile	.20
Figure A.1 – Dimensions	.38
Table 1 – Preferred values of category voltages	.10
Table 2 – Preferred tolerances	. 11
Table 3 – Temperature characteristic of capacitance	.11
Table 4 – Measuring conditions	. 14
Table 5 – Tangent of loss angle limits	. 15
Table 6 – Test voltages	. 16
Table 7 – Details of measuring conditions	.18
Table 8 – Reflow temperature profiles for Sn-Ag-Cu alloy	.20
Table 9 – Maximum capacitance change	.21
Table 10 – Maximum capacitance change	.23
Table 11 – Number of damp heat cycles	.24
Table 12 – Final inspection, measurements and requirements	.25
Table 13 – Test conditions for damp heat, steady state	.26
Table 14 – Final inspection, measurements and requirements	.26
Table 15 – Endurance test conditions ($U_C = U_R$)	.27
Table 16 – Endurance test conditions ($U_C \neq U_R$)	.27
Table 17 – Final inspection, measurements and requirements of endurance test	.28
Table 18 – Initial requirementsSIST.EM.JEC.60384-22-2024	.29
Table 19 - Conditioning ndards/sist/ccf414a0-4c14-4c92-89e1-267353242bc5/sist-en-iec-60	294-22-2024
Table 20 – Fixed sample size test plan for qualification approval Assessment level EZ	.34
Table 21 – Test schedule for qualification approval	.35
Table A.1 – Dimensions	.38
Table C.1 – Temperature characteristics of capacitance	.42
Table C.2 – Preferred values of the temperature characteristic of capacitance with and without a DC voltage applied	.43
Table C.3 – Measuring conditions of temperature characteristic of capacitance for the reference temperature 25 °C	.43
Table D.1 – Lot-by-lot inspection	
Table D.2 – Periodic test	
Table D.3 – Test schedule for quality conformance inspection (lot by lot)	.46
Table D.4 – Test schedule for quality conformance inspection (Periodic test)	
Table X.1 – Reference to IEC 60384-22 for clause/subclause	
Table X.2 – Reference to IEC 60384-22 for figure/table	.51

INTERNATIONAL ELECTROTECHNICAL COMMISSION

FIXED CAPACITORS FOR USE IN ELECTRONIC EQUIPMENT -

Part 22: Sectional specification – Fixed surface mount multilayer capacitors of ceramic dielectric, Class 2

FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested IEC National Committees.
- 3) IEC Publications have the form of recommendations for international use and are accepted by IEC National Committees in that sense. While all reasonable efforts are made to ensure that the technical content of IEC Publications is accurate, IEC cannot be held responsible for the way in which they are used or for any misinterpretation by any end user.
- 4) In order to promote international uniformity, IEC National Committees undertake to apply IEC Publications transparently to the maximum extent possible in their national and regional publications. Any divergence between any IEC Publication and the corresponding national or regional publication shall be clearly indicated in the latter.
- 5) IEC itself does not provide any attestation of conformity. Independent certification bodies provide conformity assessment services and, in some areas, access to IEC marks of conformity. IEC is not responsible for any services carried out by independent certification bodies.
- 6) All users should ensure that they have the latest edition of this publication.
- 7) No liability shall attach to IEC or its directors, employees, servants or agents including individual experts and members of its technical committees and IEC National Committees for any personal injury, property damage or other damage of any nature whatsoever, whether direct or indirect, or for costs (including legal fees) and expenses arising out of the publication, use of, or reliance upon, this IEC Publication or any other IEC Publications.
- 8) Attention is drawn to the Normative references cited in this publication. Use of the referenced publications is indispensable for the correct application of this publication.
- 9) IEC draws attention to the possibility that the implementation of this document may involve the use of (a) patent(s). IEC takes no position concerning the evidence, validity or applicability of any claimed patent rights in respect thereof. As of the date of publication of this document, IEC had not received notice of (a) patent(s), which may be required to implement this document. However, implementers are cautioned that this may not represent the latest information, which may be obtained from the patent database available at https://patents.iec.ch. IEC shall not be held responsible for identifying any or all such patent rights.

IEC 60384-22 has been prepared by IEC technical committee 40: Capacitors and resistors for electronic equipment. It is an International Standard.

This fourth edition cancels and replaces the third edition published in 2019. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

 a) the document has been completely restructured to comply with the ISO/IEC Directives, Part 2 and to make it more useable; tables, figures and references have been revised accordingly; Annex X contains all cross-references of changes in clause/subclause numbers;

- b) the requirements of reference temperature 25 °C has been added in Table 5, Table 9, Table 10, Table 12, Table 14 and Table 17;
- c) the table of temperature characteristics of capacitance for the reference temperature 25 °C have been added in Table C.1, Table C.2 and Table C.3;
- d) the requirement in 5.5.2 (visual examination) has been repeated in 5.9.3, 5.10.6, 5.11.4, 5.12.6, 5.13.8, 5.14.6 and 5.15.6;
- e) the deflection D in the very robust designs has been added in 5.9.1;
- f) Annex C has been changed informative into normative;
- g) Clause D.5 (Test schedule for quality conformance inspection) has been newly added to withdraw the blank detail specification: IEC 60384-22-1.

The text of this International Standard is based on the following documents:

Draft	Report on voting
40/3120/FDIS	40/3139/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/publications.

A list of all parts in the IEC 60384 series, published under the general title *Fixed capacitors for use in electronic equipment*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under webstore.iec.ch in the data related to the specific document. At this date, the document will be

- · reconfirmed,
- · withdrawn, or
- revised.

FIXED CAPACITORS FOR USE IN ELECTRONIC EQUIPMENT -

Part 22: Sectional specification – Fixed surface mount multilayer capacitors of ceramic dielectric, Class 2

1 Scope

This part of IEC 60384 is applicable to fixed unencapsulated surface mount multilayer capacitors of ceramic dielectric, Class 2, for use in electronic equipment. These capacitors have metallized connecting pads or soldering strips and are intended to be mounted on printed boards, or directly onto substrates for hybrid circuits.

Capacitors for electromagnetic interference suppression are not included but are covered by IEC 60384-14.

The object of this document is to specify preferred ratings and characteristics and to select from IEC 60384-1:2021 the appropriate quality assessment procedures, tests and measuring methods and to give general performance requirements for this type of capacitor. Test severities and requirements specified in detail specifications referring to this document provide specific test severities and requirements of an equal or higher performance level. Further information on the conception of generic, sectional and detail specifications can be found in the Introduction of IEC 60384-1:2021.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60068-2-58, Environmental testing – Part 2-58: Tests – Test Td – Test methods for solderability, resistance to dissolution of metallization and to soldering heat of surface mounting devices (SMD)

IEC 60384-1:2021, Fixed capacitors for use in electronic equipment – Part 1: Generic specification

IEC 61193-2:2007, Quality assessment system – Part 2: Selection and use of sampling plans for inspection of electronic components and packages

3 Terms and definitions

For the purposes of this document, the terms and definitions given in IEC 60384-1 and the following apply.

ISO and IEC maintain terminology databases for use in standardization at the following addresses:

- IEC Electropedia: available at https://www.electropedia.org/
- ISO Online browsing platform: available at https://www.iso.org/obp